# **Order Information**

Model Name	Order Number	Package	Transport Media, Quantity	Marking Information
TP8485E	TP8485E-SR	8-Pin SOIC	Tape and Reel, 4,000	TP8485E
TP8485E	TP8485E-VR	8-Pin MSOP	Tape and Reel, 3,000	TP8485E

### **DRIVER PIN FUNCTIONS**

INPUT	ENABLE	OUT	PUTS	DESCRIPTION	
D	DE	Α	В	DESCRIPTION	
				NORMAL MODE	
Н	Н	Н	L	Actively drives bus High	
L	Н	L	Н	Actively drives bus Low	
Х	L	Z	Z	Driver disabled	
Х	OPEN	Z	Z	Driver disabled by default	
OPEN	Н	Н	L	Actively drives bus High	

### **RECEIVER PIN FUNCTIONS**

			02.12.11.11.10.10.10
DIFFERENTIAL INPUT	ENABLE	OUTPUT	DESCRIPTION
$V_{ID} = V_A - V_B$	/RE	R	
			NORMAL MODE
$V_{IT+} < V_{ID}$	L	Н	Receive valid bus High
$V_{IT-} < V_{ID} < V_{IT+}$	L	?	Indeterminate bus state
$V_{ID} < V_{IT-}$	L	L	Receive valid bus Low
Х	Н	Z	Receiver disabled
Х	OPEN	Z	Receiver disabled
Open, short, idle Bus	L	Н	Indeterminate bus state

# **Absolute Maximum Ratings**

Input Voltages	V <sub>DD</sub> to GND	0.3V to +7V
Input/Output Voltages	Input Voltages	
A/Y, B/Z, A, B, Y, Z	DI, DE, RE	0.3V to (VCC + 0.3V)
A/Y, B/Z, A, B, Y, Z (Transient Pulse Through $100\Omega$ , Note 1) $\pm 100V$ RO $-0.3V$ to $(VCC + 0.3V)$ Short Circuit Duration  Y, Z Continuous  ESD Rating. See Specification Table  Recommended Operating Conditions Note 2  Supply Voltage. $3V\sim 5.5V$ Temperature Range. $-40^{\circ}C$ to $+125^{\circ}C$	Input/Output Voltages	
Note 1)	A/Y, B/Z, A, B, Y, Z	9V to +14V
RO	A/Y, B/Z, A, B, Y, Z (Transient Pulse Through $100\Omega$ ,	
Short Circuit Duration  Y, Z	Note 1)	±100V
Y, Z	RO	0.3V to (VCC +0.3V)
Recommended Operating Conditions Note 2  Supply Voltage	Short Circuit Duration	
Recommended Operating Conditions Note 2  Supply Voltage	Y, Z	Continuous
Supply Voltage	ESD Rating	See Specification Table
Temperature Range40°C to +125°C	Recommended Operating Conditions Note 2	
	Supply Voltage	3V~5.5V
Bus Pin Common Mode Voltage Range8V to +13V	Temperature Range	40°C to +125°C
	Bus Pin Common Mode Voltage Range	8V to +13V
Thermal Resistance, OJA (Typical)	Thermal Resistance, OJA (Typical)	
8-Pin SOIC Package	8-Pin SOIC Package	158°C/W
Maximum Junction Temperature (Plastic Package)+150°C	Maximum Junction Temperature (Plastic Package)	+150°C
	Maximum Storage Temperature Range	65°C to +150°C

Note 1: Tested according to TIA/EIA-485-A, Section 4.2.6 (±100V for 15µs at a 1% duty cycle).

**Note 2:** Do not operate at or near the maximum ratings listed for extended periods of time. Exposure to such conditions may adversely impact product reliability and result in failures not covered by warranty.

## **Electrical Characteristics**

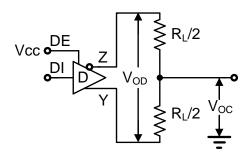
Test Conditions: VCC = 5V, Over operating free-air temperature range(unless otherwise noted)

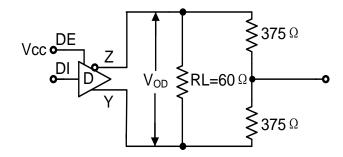
	PARAMETER	CONDITIONS		MIN	TYP	MAX	UNITS
		RL = 60 Ω	See Figure 1B		2.6		
V <sub>od</sub>	Driver differential-output voltage	RL = $54 \Omega$ with Va or VB from $-7$ to $+12$ V, Vcc = $5$ V (RS- $485$ )	See Figure 1A	2.1	2.5		
7 351	magnitude	RL = $54 \Omega$ with Va or VB from -7 to +12 V, Vcc = $3V$ (RS-485)	- Coorigate 171	1	1.5		_
		$RL = 100 \Omega (RS-422)$			3		
⊿ V <sub>od</sub>	Change in magnitude of driver differential-output voltage	RL = 54 $\Omega$ , CL=50 pF, Vcc = 5V	See Figure 1A	-0.2	-0.002	0.2	V
V <sub>OC(SS)</sub>	Steady-stage common-mode output voltage				V <sub>cc</sub> /2		V
△Voc	Change in differential driver common-mode output voltage	Center of two 27 Ω load resistors	See Figure 1A		0.05		V
V <sub>OC(PP)</sub>	Peak-to-peak driver common-mode output voltage				0.5		
C <sub>OD</sub>	Differential output capacitance				8		pF
V <sub>IT+</sub>	Positive-going receiver differential-input voltage threshold					-40	mV
V <sub>IT-</sub>	Negative-going receiver differential-input voltage threshold			-200			mV
V <sub>HYS</sub> <sup>(1)</sup>	Receiver differential-input voltage threshold hysteresis (VIT+ – VIT-)				110		mV
V <sub>IH</sub>	Logic Input High Voltage	DI, DE, RE		2			V
V <sub>IL</sub>	Logic Input Low Voltage	DI, DE, RE				0.4	V
V <sub>OH</sub>	Receiver high-level output voltage	I <sub>OH</sub> = -8 mA		4	4.5		V
V <sub>OL</sub>	Receiver low-level output voltage	I <sub>OL</sub> = 8 mA			0.2	0.4	V
I <sub>I</sub>	Driver input, driver enable and receiver enable input current	OL CHA!		-2	0.01	2	μΑ
I <sub>OZ</sub>	Receiver high-impedance output current	VO = 0 V or VCC, /RE a	t VCC	-2	0.01	2	μА
I <sub>os</sub>	Driver short-circuit output current	los   with VA or VB from	n –7 to +12 V	75	80	115	mA
	Due input engage (daily and Parklan)	Vcc = 4.5 to 5.5 V or	VI= 12 V		100	150	
I <sub>I</sub>	Bus input current(driver disabled)	Vcc = 0 V, DE at 0 V	VI= -7 V	-150	-80		μA
		Driver and receiver enabled	DE = Vcc, /RE = GND, No LOAD		695	900	
		Driver enabled, receiver disabled	$DE = Vcc,$ $/RE = V_{CC}, No$ $LOAD$		270	350	
I <sub>CC</sub>	Supply current(quiescent)	Driver disabled, receiver enabled	DE = GND, /RE = V <sub>CC</sub> , No LOAD		480	600	μΑ
		Driver and receiver disabled	DE = GND, /RE = V <sub>CC</sub> , D= V <sub>cc</sub> No LOAD		1.4	5	

# **Switching CHARACTERISTICS**

	PARAMETER	CONDITIONS		MIN	TYP	MAX	UNITS
DRIVER		1					
t <sub>r</sub> , t <sub>f</sub>	Driver differential-output rise and fall times	- RL = 54 Ω, CL=50pF			620		
t <sub>PHL</sub> , t <sub>PLH</sub>	Driver propagation delay	KL = 54 \(\Omega\), GL-50pF	See Figure 2		340		ns
tsk(P)	Driver pulse skew,  tphl - tplh				23		
tphz, tplz	Driver disable time				250		ns
4	Driver english times	Receiver enabled	See Figure 3		562		
tpHZ, tpLZ	Driver enable time	Receiver disabled			562		ns
RECEIVER							
tr, tf	Receiver output rise and fall times				12.4		
tPHL, tPLH	Receiver propagation delay time	CL=15 pF	See Figure 5		960		ns
tsk(P)	Receiver pulse skew,  tphl – tplh				40		
tpHZ, tpLZ	Receiver disable time				7		ns
		Driver enabled	See Figure 6		70		
tPZL, tPZH	Receiver enable time	Driver disabled	See Figure 6		989		ns
ESD		1	•			I	
RS-485							
Pins (A, Y,		Human Body Model, F	rom Bus Pins to				
B, Z, A/Y,		GND			±12		kV
B/Z)							
All Other							
Pins		Human Body Model, p	er MIL-STD-883		±2		kV
FIII5							

#### **Test Circuits and Waveforms**

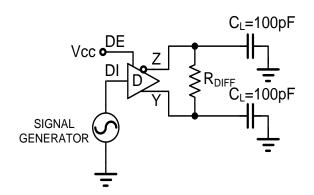


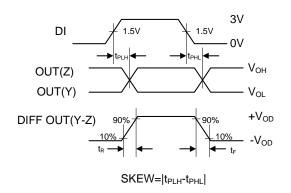


**FIGURE 1A. VOD AND VOC** 

FIGURE 1B. VOD WITH COMMON MODE LOAD

FIGURE 1. DC DRIVER TEST CIRCUITS

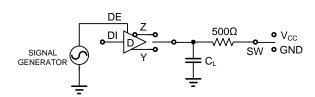




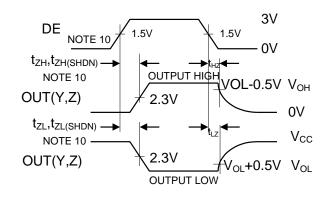
### FIGURE 2A. TEST CIRCUIT

FIGURE 2B. MEASUREMENT POINTS

FIGURE 2. DRIVER PROPAGATION DELAY AND DIFFERENTIAL TRANSITION TIMES



PARAMETER	OUTPUT	RE	DI	sw	CL
TANAMETER	001101	KL	Di	300	(pF)
tHZ	Y/Z	X	1/0	GND	15
tLZ	Y/Z	Х	0/1	VCC	15
tZH	Y/Z	0	1/0	GND	100
tZL	Y/Z	0	0/1	VCC	100
tZH(SHDN)	Y/Z	1	1/0	GND	100
tZL(SHDN)	Y/Z	1	0/1	VCC	100

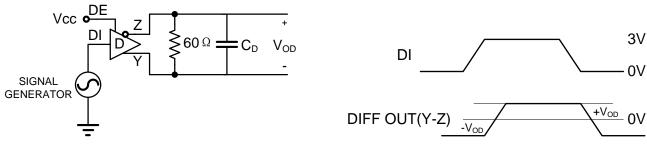


**FIGURE 3A. TEST CIRCUIT** 

FIGURE 3B. MEASUREMENT POINTS

FIGURE 3. DRIVER ENABLE AND DISABLE TIMES

## Test Circuits and Waveforms(continue)



**FIGURE 4A. TEST CIRCUIT** 

**FIGURE 4B. MEASUREMENT POINTS** 

**FIGURE 4. DRIVER DATA RATE** 

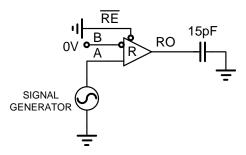


FIGURE 5A. TEST CIRCUIT

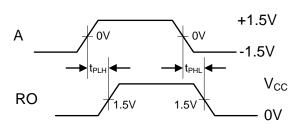
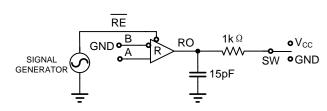


FIGURE 5B. MEASUREMENT POINTS

FIGURE 5. RECEIVER PROPAGATION DELAY AND DATA RATE



PARAMETER	DE	Α	sw
tHZ	1	+1.5V	GND
tLZ	1	-1.5V	VCC
tZH	1	+1.5V	GND
tZL	1	-1.5V	VCC
tZH(SHDN)	0	+1.5V	GND
tZL(SHDN)	0	-1.5V	VCC

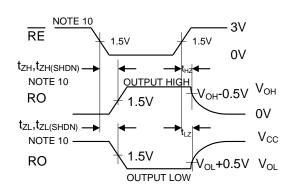


FIGURE 6A. TEST CIRCUIT

FIGURE 6B. MEASUREMENT POINTS

FIGURE 6. RECEIVER ENABLE AND DISABLE TIMES

### **Detailed Description**

RS-485 and RS-422 are differential (balanced) data transmission standards used for long haul or noisy environments. RS-422 is a subset of RS-485, so RS-485 transceivers are also RS-422 compliant. RS-422 is a point-to-multipoint (multidrop) standard, which allows only one driver and up to 10 (assuming one unit load devices) receivers on each bus. RS-485 is a true multipoint standard, which allows up to 32 one unit load devices (any combination of drivers and receivers) on each bus. To allow for multipoint operation, the RS-485 specification requires that drivers must handle bus contention without sustaining any damage. Another important advantage of RS-485 is the extended common mode range (CMR), which specifies that the driver outputs and receiver inputs withstand signals that range from +12V to -7V. RS-422 and RS-485 are intended for runs as long as 4000', so the wide CMR is necessary to handle ground potential differences, as well as voltages induced in the cable by external fields.

#### Receiver (Rx) Features

TP8485E utilize a differential input receiver for maximum noise immunity and common mode rejection. Input sensitivity is better than  $\pm 200$  mV, as required by the RS-422 and RS-485 specifications. Rx outputs feature high drive levels (typically 25mA @ VOL = 1V) to ease the design of optically coupled isolated interfaces. Receiver input resistance of 100k $\Omega$  surpasses the RS-422 specification of 4k $\Omega$ , and is eight times the RS-485 "Unit Load (UL)" requirement of 12k $\Omega$  minimum. Thus, these products are known as "one-eighth UL" transceivers, and there can be up to 256 of these devices on a network while still complying with the RS-485 loading specification. Rx inputs function with common mode voltages as great as  $\pm 7$ V outside the power supplies (i.e.,  $\pm 12$ V and  $\pm 12$ V), making them ideal for long networks where induced voltages are a realistic concern. All the receivers include a "full fail-safe" function that guarantees a high level receiver output if the receiver inputs are unconnected (floating), shorted together, or connected to a terminated bus with all the transmitters disabled. Receivers easily meet the data rates supported by the corresponding driver, and all receiver outputs are three-stable via the active low RE input.

#### **Driver (Tx) Features**

TP8485E driver is a differential output device that delivers at least 2.5V across a  $54\Omega$  load (RS-485), and at least 2.8V across a  $100\Omega$  load (RS-422). The drivers feature low propagation delay skew to maximize bit width, and to minimize EMI, and all drivers are three-stable via the active high DE input.

#### **Full Fail-Safe**

All the receivers include a "full fail-safe" function that guarantees a high level receiver output if the receiver inputs are unconnected (floating), shorted together, or connected to a terminated bus with all the transmitters disabled. Receivers easily meet the data rates supported by the corresponding driver, and all receiver outputs are three-statable via the active low RE input.

#### **Hot Plug Function**

When a piece of equipment powers up, there is a period of time where the processor or ASIC driving the RS-485 control lines (DE, RE) is unable to ensure that the RS-485 Tx and Rx outputs are kept disabled. If the equipment is connected to the bus, a driver activating prematurely during power-up may crash the bus. To avoid this scenario, the TP8485E devices incorporate a "Hot Plug" function. Circuitry monitoring VCC ensures that, during power-up and power-down, the Tx and Rx outputs remain disabled, regardless of the state of DE and RE, if VCC is less than ~2.5V. This gives the processor/ASIC a chance to stabilize and drive the RS-485 control lines to the proper states.

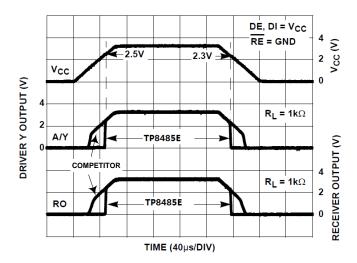


FIGURE 8. HOT PLUG PERFORMANCE (TP8485E) vs Competitor WITHOUT HOT PLUG CIRCUITRY

#### **Transient Protection**

The bus terminals of the TP8485E transceiver family possess on-chip ESD protection against  $\pm 12$ kV HBM. The International Electrotechnical Commission (IEC) ESD test is far more severe than the HBM ESD test. The 50% higher charge capacitance, CS, and 78% lower discharge resistance, RD of the IEC model produce significantly higher discharge currents han the HBM model. As stated in the IEC 61000-4-2 standard, contact discharge is the preferred transient protection test method. Although IEC air-gap testing is less repeatable than contact testing, air discharge protection levels are inferred from the contact discharge test results.

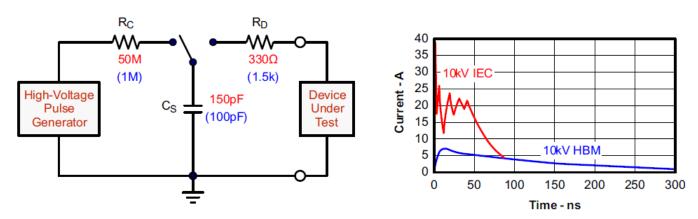
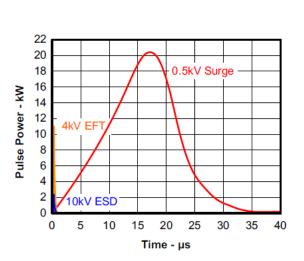


Figure 9. HBM and IEC-ESD Models and Currents in Comparison (HBM Values in Parenthesis)

The on-chip implementation of IEC ESD protection significantly increases the robustness of equipment. Common discharge events occur because of human contact with connectors and cables. Designers may choose to implement protection against longer duration transients, typically referred to as surge transients. Figure 9 suggests two circuit designs providing protection against short and long duration surge transients, in addition to ESD and Electrical Fast Transients (EFT) transients. Table 1 lists the bill of materials for the external protection devices.

EFTs are generally caused by relay-contact bounce or the interruption of inductive loads. Surge transients often result from lightning strikes (direct strike or an indirect strike which induce voltages and currents), or the switching of power systems, including load changes and short circuits switching. These transients are often encountered in industrial environments, such as factory automation and power-grid systems. Figure 10 compares the pulse-power of the EFT and surge transients with the power caused by an IEC ESD transient. In the diagram on the left of Figure 10, the tiny blue blip in the bottom left corner represents the power of a 10-kV ESD

transient, which already dwarfs against the significantly higher EFT power spike, and certainly dwarfs against the 500-V surge transient. This type of transient power is well representative of factory environments in industrial and process automation. The diagram on the fright of Figure 10 compares the enormous power of a 6-kV surge transient, most likely occurring in e-metering applications of power generating and power grid systems, with the aforementioned 500-V surge transient.



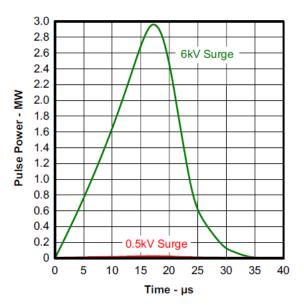


Figure 10. Power Comparison of ESD, EFT, and Surge Transients

In the case of surge transients, high-energy content is signified by long pulse duration and slow decaying pulse Power The electrical energy of a transient that is dumped into the internal protection cells of the transceiver is converted into thermal energy. This thermal energy heats the protection cells and literally destroys them, thus destroying the transceiver. Figure 11 shows the large differences in transient energies for single ESD, EFT, and surge transients as well as for an EFT pulse train, commonly applied during compliance testing.

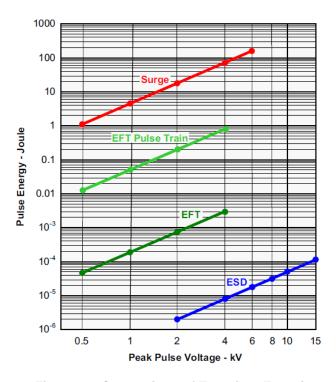


Figure 11. Comparison of Transient Energies

### **Table 1. Bill of Materials**

Device	Function	Order Number	Manufacturer
485	5-V, 250-kbps RS-485 Transceiver	TP8485E	3PEAK
R1, R2	10-Ω, Pulse-Proof Thick-Film Resistor	CRCW0603010RJNEAHP	Vishay
TVS	Bidirectional 400-W Transient Suppressor	CDSOT23-SM712	Bourns
TBU1, TBU2	Bidirectional	TBU-CA-065-200-WH	Bourns
MOV1, MOV2	200mA Transient Blocking Unit 200-V, Metal- Oxide Varistor	MOV-10D201K	Bourns

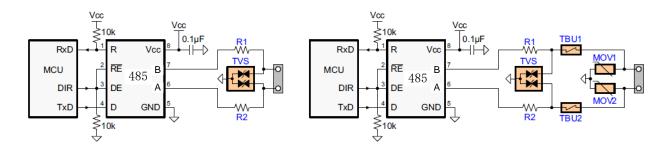


Figure 12. Transient Protections Against ESD, EFT, and Surge Transients

The left circuit shown in Figure 12 provides surge protection of  $\geq$  500-V transients, while the right protection circuits can withstand surge transients of 5 kV

### **Typical Performance Characteristics**

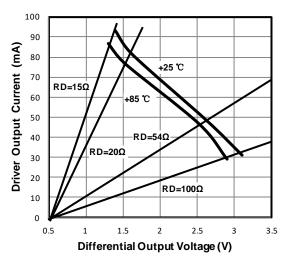


FIGURE 13. DRIVER OUTPUT CURRENT vs

VOLTAGE DIFFERENTIAL OUTPUT VOLTAGE

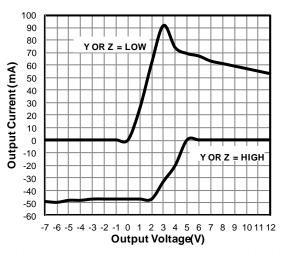


FIGURE 15. DRIVER OUTPUT CURRENT vs SHORT
CIRCUIT VOLTAGE

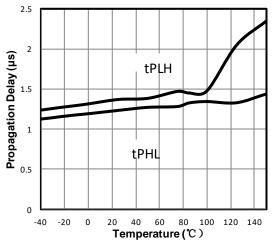


FIGURE 17. DRIVER DIFFERENTIAL PROPAGATION
DELAY vs TEMPERATURE

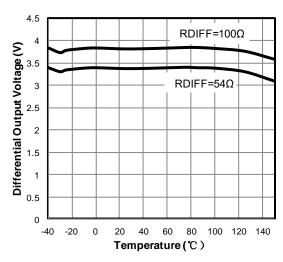


FIGURE 14. DRIVER DIFFERENTIAL OUTPUT

vs TEMPERATURE

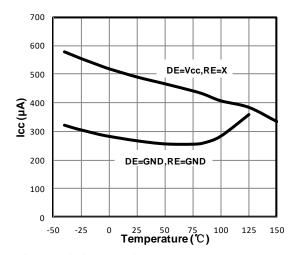


FIGURE 16. SUPPLY CURRENT vs TEMPERATURE

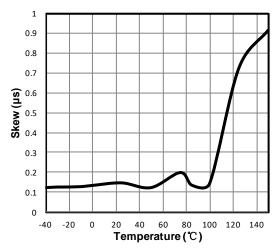


FIGURE 18. DRIVER DIFFERENTIAL SKEW vs
TEMPERATURE

## **Typical Performance Curves** VCC = 5V, TA = +25°C; Unless Otherwise Specified.

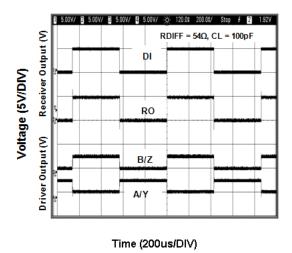


FIGURE 19. DRIVER AND RECEIVER WAVEFORMS

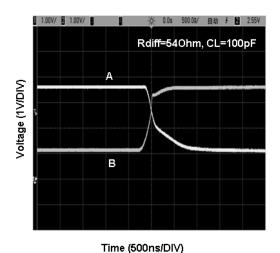
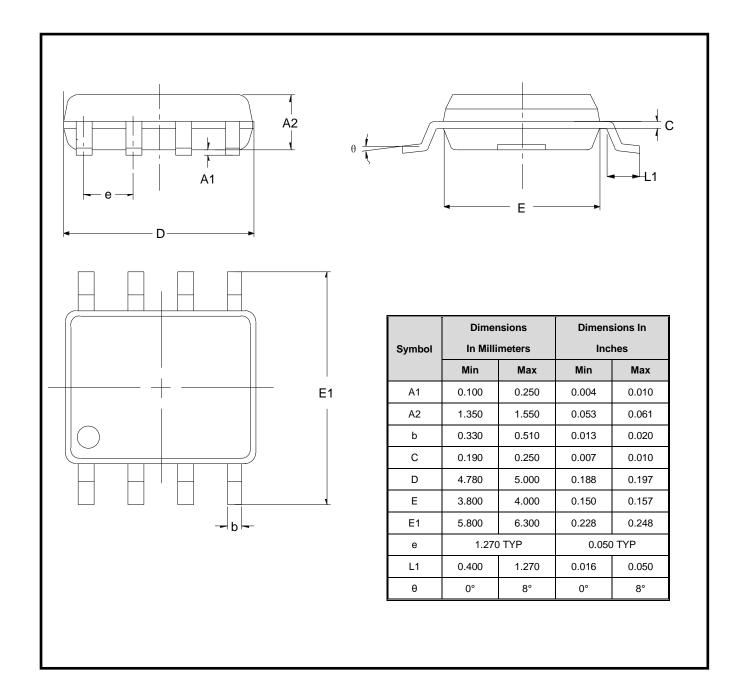


FIGURE 20. DRIVER WAVEFORMS

# **Package Outline Dimensions**

SO-8 (SOIC-8)



# **Package Outline Dimensions**

MSOP-8

